## IVN Bus Protector, Single Line LIN & Dual Line CAN

# NUP1128, NUP2128

The NUP1128/NUP2128 are designed to protect both CAN and LIN transceivers from ESD and other harmful transient voltage events. These devices provide bidirectional protection for each data line with a single compact SC-70 (SOT-323) or SOD-323 package, giving the system designer a low cost option for improving system reliability and meeting stringent EMI requirements.

### Features

- Low Reverse Leakage Current (< 100 nA)
- SZNUPH1128, SZNUP2128 175°C T<sub>J(max)</sub> Devices
  - Rated for High Temperature, Mission Critical and Grade 0 Applications
- IEC Compatibility:
  - IEC 61000-4-2 (ESD): Level 4
  - IEC 61000-4-4 (EFT): 50 A (5/50 ns)
  - + IEC 61000-4-5 (Lighting) 3.0 A (8/20 μs)
- ISO 7637–1, Nonrepetitive EMI Surge Pulse 2, 8.0 A (1/50 μs)
- ISO 7637–3, Repetitive Electrical Fast Transient (EFT) EMI Surge Pulses, 50 A (5/50 ns)
- Flammability Rating UL 94 V-0
- SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC–Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

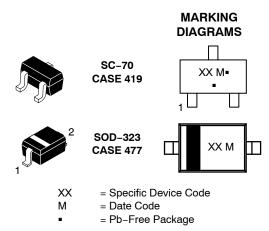
### Applications

- Automotive Networks
  - ◆ CAN / CAN-FD
  - Low and High-Speed CAN
  - Fault Tolerant CAN
  - + LIN

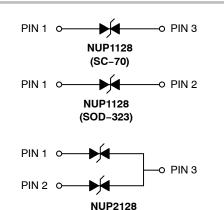


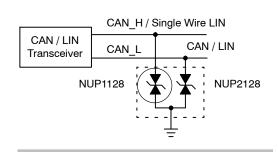
## **ON Semiconductor®**

www.onsemi.com



(Note: Microdot may be in either location)





#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 7 of this data sheet.

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C, unless otherwise specified)

Symbol	Rating	Value	Unit
PPK	Peak Power Dissipation, 8/20 $\mu s$ Double Exponential Waveform (Note 1)	165	W
TJ	Operating Junction Temperature Range NUP1128HT1G, SZNUP1128HT1G All other devices	–55 to 150 –55 to 175	°C
TJ	Storage Temperature Range NUP1128HT1G, SZNUP1128HT1G All other devices	–55 to 150 –55 to 175	℃
TL	Lead Solder Temperature (10 s)	260	°C
ESD	Human Body Model (HBM) IEC 61000–4–2 Contact IEC 61000–4–2 Air ISO 10605 Contact (330 pF / 330 Ω) ISO 10605 Contact (330 pF / 2 kΩ) ISO 10605 Contact (150 pF / 2 kΩ)	$\begin{array}{c} 8.0 \\ \pm 30 \end{array}$	kV kV kV kV kV kV

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Non-repetitive current pulse per Figure 1.

#### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C, unless otherwise specified)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>RWM</sub>	Reverse Working Voltage	(Note 2)			26.5	V
V <sub>BR</sub>	Breakdown Voltage	I <sub>T</sub> = 1 mA (Note 3)	27.5	31	35.5	V
I <sub>R</sub>	Reverse Leakage Current	V <sub>RWM</sub> = 26.5 V T <sub>A</sub> = 150°C		1 150	100 750	nA
V <sub>C</sub>	Clamping Voltage	$I_{PP} = 1 \text{ A} (8/20 \ \mu \text{s Waveform}) \text{ (Note 4)}$ $I_{PP} = 3 \text{ A}$		39 46	47 55	V
I <sub>PP</sub>	Maximum Peak Pulse Current	8/20 μs Waveform (Note 4)	3.0			А
CJ	Capacitance	V <sub>R</sub> = 0 V, f = 1 MHz (Line to GND)		11	13	pF
ΔC	Diode Capacitance Matching	V <sub>R</sub> = 0 V, f = 1 MHz (Note 5)			2	%

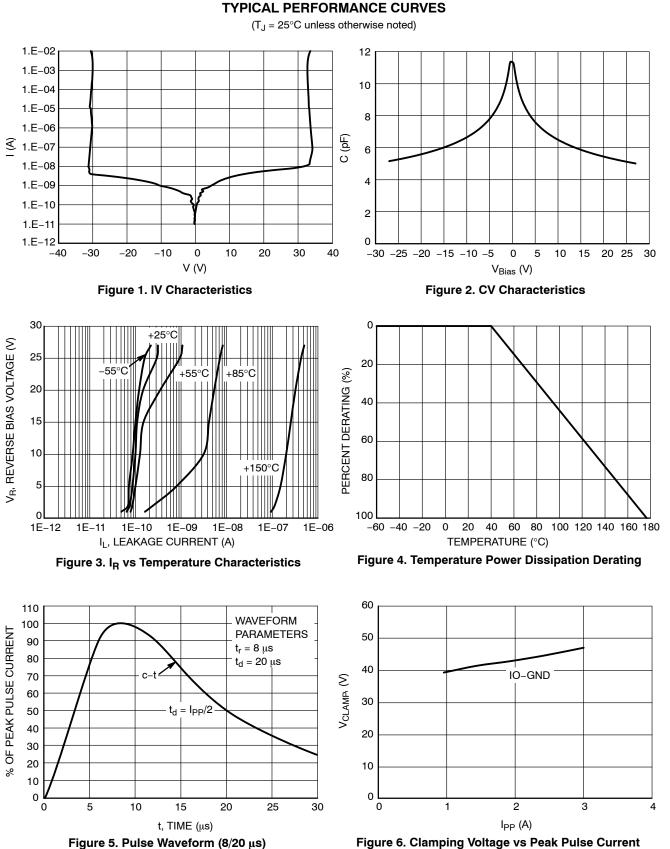
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

2. TVS devices are normally selected according to the working peak reverse voltage (V<sub>RWM</sub>), which should be equal or greater than the DC or continuous peak operating voltage level.

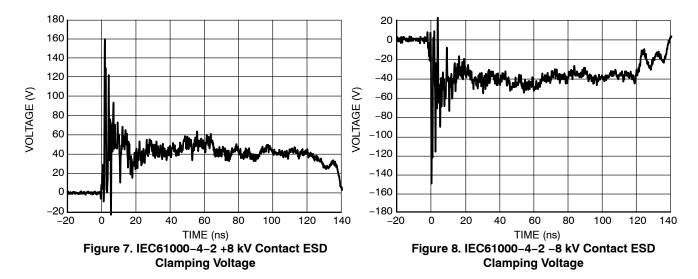
3. V<sub>BR</sub> is measured at pulse test current I<sub>T</sub>.

4. Pulse waveform per Figure 1.

5. ΔC is the percentage difference between C<sub>J</sub> of lines 1 and 2 measured according to the test conditions given in the electrical characteristics table.

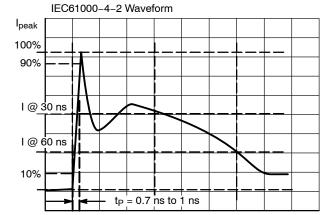


(8/20 μs)



### IEC 61000-4-2 Spec.

Level	Test Volt- age (kV)	First Peak Current (A)	Current at 30 ns (A)	Current at 60 ns (A)
1	2	7.5	4	2
2	4	15	8	4
3	6	22.5	12	6
4	8	30	16	8





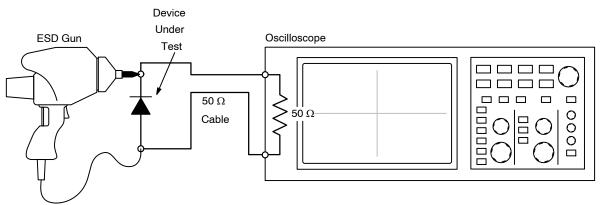


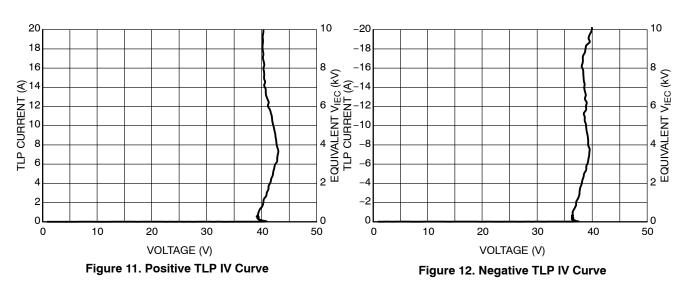
Figure 10. Diagram of ESD Clamping Voltage Test Setup

#### The following is taken from Application Note AND8308/D – Interpretation of Datasheet Parameters for ESD Devices.

#### **ESD Voltage Clamping**

For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000–4–2 waveform. Since the IEC61000–4–2 was written as a pass/fail spec for larger

systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage at the device level. ON Semiconductor has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how ON Semiconductor creates these screenshots and how to interpret them please refer to AND8307/D.



NOTE: TLP parameter:  $Z_0 = 50 \Omega$ ,  $t_p = 100 \text{ ns}$ ,  $t_r = 300 \text{ ps}$ , averaging window:  $t_1 = 30 \text{ ns}$  to  $t_2 = 60 \text{ ns}$ .

#### Transmission Line Pulse (TLP) Measurement

Transmission Line Pulse (TLP) provides current versus voltage (I–V) curves in which each data point is obtained from a 100 ns long rectangular pulse from a charged transmission line. A simplified schematic of a typical TLP system is shown in Figure 13. TLP I–V curves of ESD protection devices accurately demonstrate the product's ESD capability because the 10s of amps current levels and under 100 ns time scale match those of an ESD event. This is illustrated in Figure 14 where an 8 kV IEC 61000–4–2 current waveform is compared with TLP current pulses at 8 A and 16 A. A TLP I–V curve shows the voltage at which the device turns on as well as how well the device clamps voltage over a range of current levels.

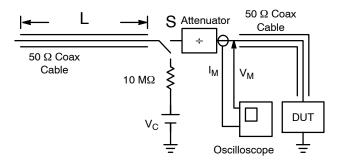


Figure 13. Simplified Schematic of a Typical TLP System

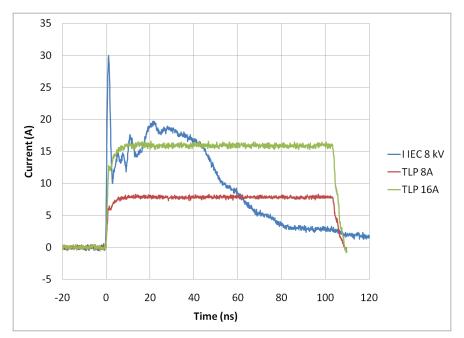


Figure 14. Comparison Between 8 kV IEC 61000-4-2 and 8 A and 16 A TLP Waveforms

#### **ORDERING INFORMATION**

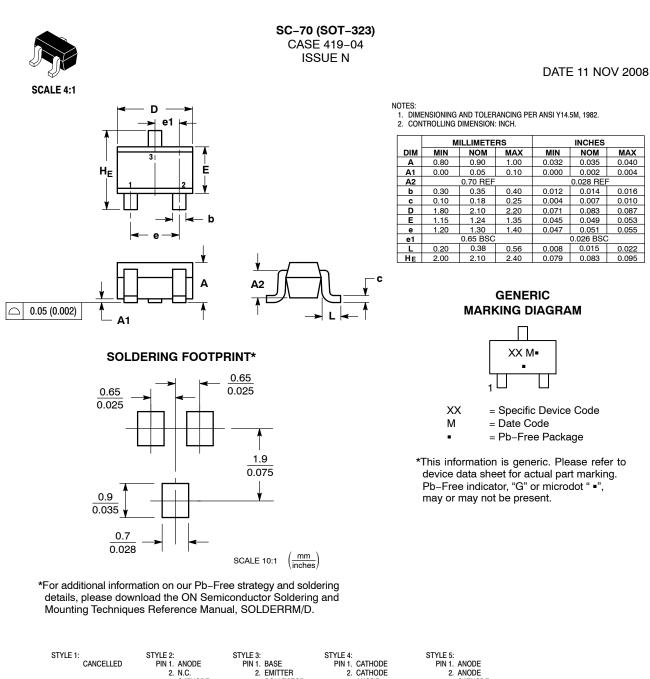
Device	Marking	Package	Operating Junction Temperature Range	Shipping <sup>†</sup>	
NUP1128WTT1G	7X				
SZNUP1128WTT1G*	78	SC–70 (Pb–Free)			
NUP2128WTT1G	711			3000 / Tape & Reel	
SZNUP2128WTT1G*	7U		–55 to 175°C		
NUPH1128HT1G	A.			– 3000 / Tape & Reel	
SZNUPH1128HT1G*	AL	SOD-323			
NUP1128HT1G	7.4	(Pb-Free)	55 1 45000		
SZNUP1128HT1G*	7A		–55 to 150°C		

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.
 \*SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP

Capable.

Honeywell and SDS are registered trademarks of Honeywell International Inc. DeviceNet is a trademark of Rockwell Automation.





	3. CATHODE	3. COLLECTOR	3. ANODE	3. CATHODE	
Style 6:	STYLE 7:	STYLE 8:	STYLE 9:	Style 10:	STYLE 11:
Pin 1. Emitter	PIN 1. BASE	PIN 1. GATE	Pin 1. Anode	Pin 1. Cathode	PIN 1. CATHODE
2. Base	2. EMITTER	2. SOURCE	2. Cathode	2. Anode	2. CATHODE
3. Collector	3. COLLECTOR	3. DRAIN	3. Cathode-Anode	3. Anode-Cathode	3. CATHODE

DOCUMENT NUMBER:	98ASB42819B	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	SC-70 (SOT-323)		PAGE 1 OF 1	

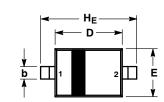
ON Semiconductor and unarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights or the rights of others.

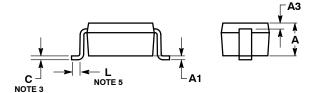
© Semiconductor Components Industries, LLC, 2019



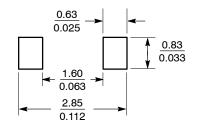








#### **SOLDERING FOOTPRINT\***



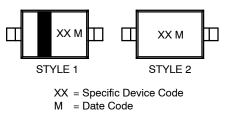
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DATE 13 MAR 2007

- NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: MILLIMETERS. 3. LEAD THICKNESS SPECIFIED PER L/F DRAWING WITH SOLDER PLATING. 1. DIMENSIONAL AND R. DO. NOT. NOLLINE MOLD.
- WITH SOLDER PLATING.
  4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS.
  5. DIMENSION L IS MEASURED FROM END OF RADIUS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.80	0.90	1.00	0.031	0.035	0.040	
A1	0.00	0.05	0.10	0.000	0.002	0.004	
A3	0.15 REF		F	0.006 REF			
b	0.25	0.32	0.4	0.010	0.012	0.016	
С	0.089	0.12	0.177	0.003	0.005	0.007	
D	1.60	1.70	1.80	0.062	0.066	0.070	
E	1.15	1.25	1.35	0.045	0.049	0.053	
L	0.08			0.003			
HE	2.30	2.50	2.70	0.090	0.098	0.105	

#### GENERIC **MARKING DIAGRAM\***



\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present.

DOCUMENT NUMBER:	98ASB17533C	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.						
DESCRIPTION:	DESCRIPTION: SOD-323 PAGE							
ON Semiconductor reserves the right the suitability of its products for any pa	ON Semiconductor and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the							

SOD-323 CASE 477-02

**ISSUE H** 

STYLE 1: PIN 1. CATHODE (POLARITY BAND) 2. ANODE STYLE 2: NO POLARITY

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <u>www.onsemi.com/site/pdf/Patent-Marking.pdf</u>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor date sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use a a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor houteds for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries

#### PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT:

#### TECHNICAL SUPPORT

ON Semiconductor Website: www.onsemi.com

Email Requests to: orderlit@onsemi.com

North American Technical Support: Voice Mail: 1 800–282–9855 Toll Free USA/Canada Phone: 011 421 33 790 2910 Europe, Middle East and Africa Technical Support: Phone: 00421 33 790 2910 For additional information, please contact your local Sales Representative

## **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for ESD Suppressors / TVS Diodes category:

Click to view products by ON Semiconductor manufacturer:

Other Similar products are found below :

60KS200C D12V0H1U2WS-7 D18V0L1B2LP-7B 82356050220 D5V0M5U6V-7 NTE4902 P4KE27CA P6KE11CA P6KE39CA-TP P6KE8.2A SA110CA SA60CA SA64CA SMBJ12CATR SMBJ8.0A SMLJ30CA-TP ESD101-B1-02ELS E6327 ESD112-B1-02EL E6327 ESD119B1W01005E6327XTSA1 ESD5V0J4-TP ESD5V0L1B02VH6327XTSA1 ESD7451N2T5G 19180-510 CPDT-5V0USP-HF 3.0SMCJ33CA-F 3.0SMCJ36A-F HSPC16701B02TP D3V3Q1B2DLP3-7 D55V0M1B2WS-7 DESD5V0U1BL-7B DRTR5V0U4SL-7 SCM1293A-04SO ESD200-B1-CSP0201 E6327 ESD203-B1-02EL E6327 SM12-7 SMF8.0A-TP SMLJ45CA-TP CEN955 W/DATA 82350120560 82356240030 VESD12A1A-HD1-GS08 CPDUR5V0R-HF CPDUR24V-HF CPDQC5V0U-HF CPDQC5V0USP-HF CPDQC5V0-HF D1213A-01LP4-7B D1213A-02WL-7 ESDLIN1524BJ-HQ 5KP100A